

# FDMA2002NZ

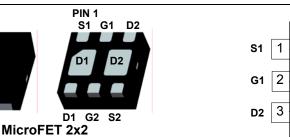
## **Dual N-Channel PowerTrench<sup>®</sup> MOSFET**

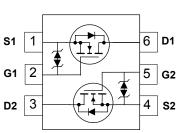
### **General Description**

This device is designed specifically as a single package solution for dual switching requirements in cellular handset and other ultra-portable applications. It features two independent N-Channel MOSFETs with low on-state resistance for minimum conduction losses. The MicroFET 2x2 offers exceptional thermal performance for its physical size and is well suited to linear mode applications.

### Features

- 2.9 A, 30 V  $R_{DS(ON)}$  = 123 m $\Omega$  @ V<sub>GS</sub> = 4.5 V  $R_{DS(ON)}$  = 140 m $\Omega$  @ V<sub>GS</sub> = 3.0 V  $R_{DS(ON)}$  = 163 m $\Omega$  @ V<sub>GS</sub> = 2.5 V
- Low profile 0.8 mm maximum in the new package MicroFET 2x2 mm
- HBM ESD protection level = 1.8kV (Note 3)
- RoHS Compliant





### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DS</sub>	Drain-Source Voltage		30	V
V <sub>GS</sub>	Gate-Source Voltage		±12	V
I <sub>D</sub>	Drain Current – Continuous ( $T_c = 25^{\circ}C$ , $V_{GS} = 4.5^{\circ}$	/)	2.9	
	– Continuous ( $T_c$ = 25°C, $V_{GS}$ = 2.5°	V)	2.7	A
	– Pulsed		10	
P <sub>D</sub>	Power Dissipation for Single Operation	(Note 1a)	1.5	
	Power Dissipation for Single Operation	(Note 1b)	0.65	- W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature		-55 to +150	°C

### **Thermal Characteristics**

$R_{ ext{ heta}JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	83 (Single Operation)	
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	193 (Single Operation)	°C/W
$R_{\thetaJA}$	Thermal Resistance, Junction-to-Ambient	(Note 1c)	68 (Dual Operation)	C/W
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1d)	145 (Dual Operation)	

### Package Marking and Ordering Information

_	Device Marking	Device	Reel Size	Tape width	Quantity
	002	FDMA2002NZ	7"	8mm	3000 units

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<b>Off Char</b> BV <sub>DSS</sub>	Parameter	Test Conditions	Min	Тур	Max	Units
	acteristics					
	Drain–Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	30			V
<u>ΔBV<sub>DSS</sub></u> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 µA, Referenced to 25°C		25		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 24 V$ , $V_{GS} = 0 V$			1	μA
I <sub>GSS</sub>	Gate-Body Leakage Current	$V_{GS} = \pm 12 V$ , $V_{DS} = 0 V$			±10	μA
On Char	acteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$	0.4	1.0	1.5	V
$\Delta V_{GS(th)}$ $\Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D$ = 250 µA, Referenced to 25°C		-3		mV/°C
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 2.9A		75	123	
		V <sub>GS</sub> = 3.0V, I <sub>D</sub> = 2.7A		84	140	
R <sub>DS(on)</sub>	Static Drain–Source	$V_{GS} = 2.5V, I_D = 2.5A$		92	163	mΩ
/	On–Resistance	$V_{GS} = 4.5V, I_D = 2.9A, T_C = 85^{\circ}C$	+	95	166	
		$V_{GS}$ = 3.0V, $I_D$ = 2.7A, $T_C$ = 150°C $V_{GS}$ = 2.5V, $I_D$ = 2.5A, $T_C$ = 150°C	+	138 150	203 268	
Dunamia	Characteristics	V <sub>GS</sub> = 2.3V, I <sub>D</sub> = 2.3A, I <sub>C</sub> = 150 C		150	200	
Dynamic C <sub>iss</sub>	Characteristics		1	190	220	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz		30	40	pF
	Reverse Transfer Capacitance			20	30	pr
				20	50	рі
	g Characteristics (Note 2)	$V_{DD} = 15 V$ , $I_{D} = 1 A$ ,	1	<u> </u>	10	
t <sub>d(on)</sub>	Turn–On Delay Time	$V_{DD} = 15 V$ , $T_D = 1 A$ , $V_{GS} = 4.5 V$ , $R_{GEN} = 6 \Omega$		6	12	ns
t <sub>r</sub>	Turn–On Rise Time	$V_{\rm GS} = 4.0$ V, $V_{\rm GEN} = 0.22$		8	16	ns
t <sub>d(off)</sub>	Turn–Off Delay Time	-		12	21	ns
+	Turn–Off Fall Time		_	2	10	ns
	Total Gate Charge	$V_{DS} = 15 V$ , $I_D = 2.9 A$ , $V_{GS} = 4.5 V$		2.4	3.0	nC
Q <sub>g</sub>				0.35		nC
Q <sub>g</sub>	Gate–Source Charge					
Q <sub>g</sub> Q <sub>gs</sub>				0.75		nC
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Gate–Source Charge			0.75		nC
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub> Drain–Sc Is	Gate–Source Charge Gate–Drain Charge	and Maximum Ratings		0.75	2.9	nC A
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub> Drain–Sc Is	Gate–Source Charge Gate–Drain Charge Durce Diode Characteristics	and Maximum Ratings		0.75 0.9 0.8	2.9 1.2 1.2	I
t <sub>r</sub> Q <sub>g</sub> Q <sub>gs</sub> Drain–So Is V <sub>SD</sub>	Gate–Source Charge Gate–Drain Charge Durce Diode Characteristics Maximum Continuous Drain–Source Drain–Source Diode Forward	and Maximum Ratings e Diode Forward Current I <sub>s</sub> = 2.0 A		0.9	1.2	A

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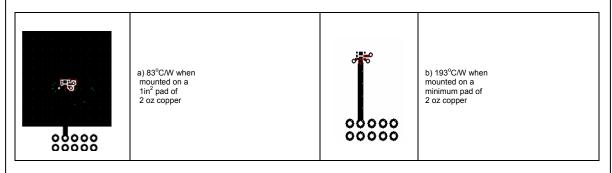
### **Electrical Characteristics**

#### $T_A = 25^{\circ}C$ unless otherwise noted

#### Notes:

1.  $R_{0,A}$  is determined with the device mounted on a 1 in<sup>2</sup> oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{0,JC}$  is guaranteed by design while  $R_{0,A}$  is determined by the user's board design. (a)  $R_{0,JA} = 83^{\circ}C/W$  when mounted on a 1in<sup>2</sup> pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB

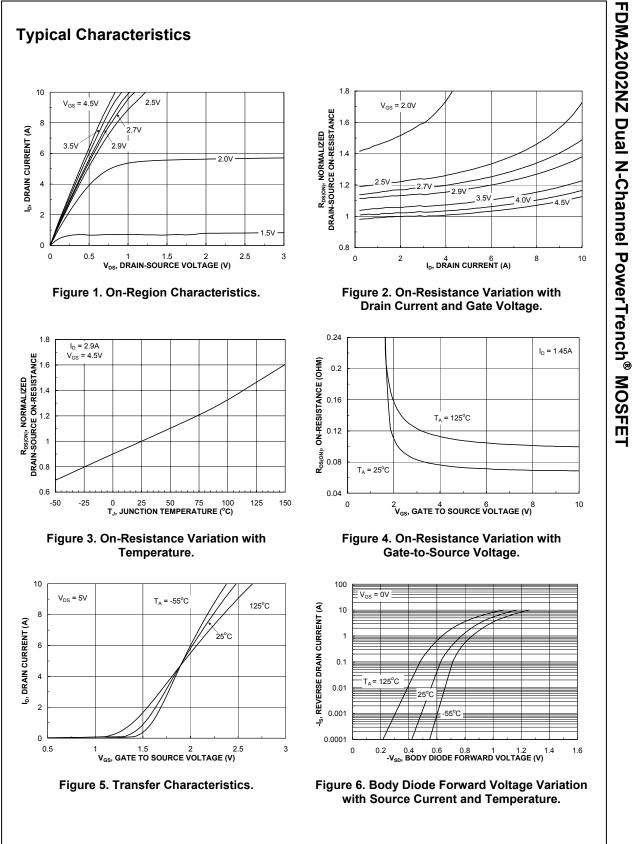
- (b)  $R_{0JA}^{\circ}$  = 193°C/W when mounted on a minimum pad of 2 oz copper
- (c)  $R_{\theta JA}^{2}$  = 68°C/W when mounted on a 1in<sup>2</sup> pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB
- (d)  $R_{0,IA} = 145^{\circ}C/W$  when mounted on a minimum pad of 2 oz copper

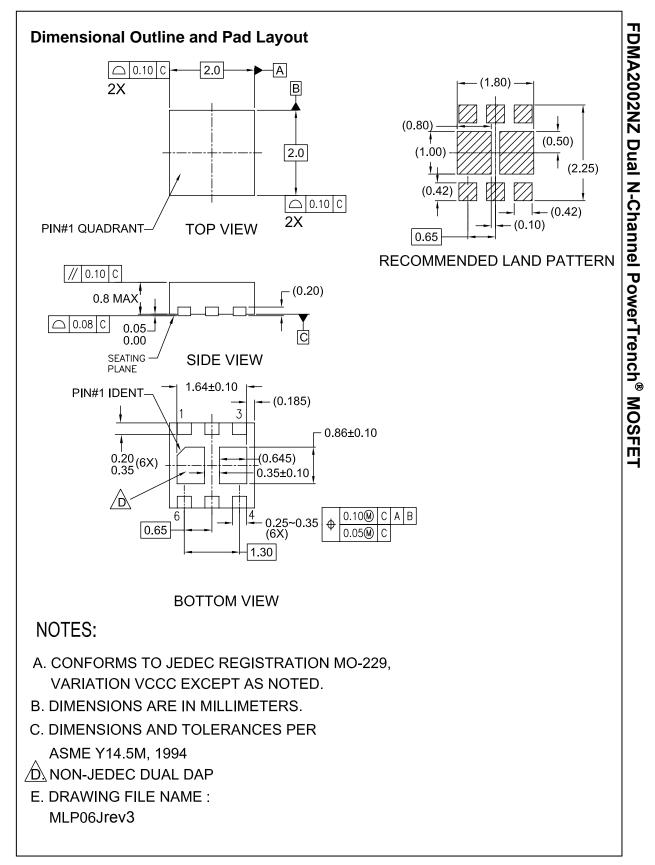


Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width <  $300\mu$ s, Duty Cycle < 2.0%

3. The diode connected between the gate and source serves only protection against ESD. No gate overvoltage rating is implied.





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